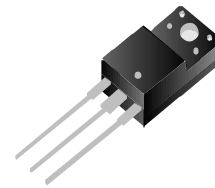
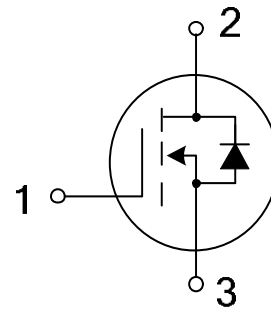


AP8N80F

N-Channel Enhancement Mosfet

Features

- 800V,8A
 $R_{DS(ON)} < 1.55 \Omega @ V_{GS}=10V$ TYP:1.42 Ω
- Low gate charge
- Low Crss
- Fast switching
- Improved dv/dt capability



TO-220F

Applications

- AC-DC power suppliers,
- DC-DC converters
- H-bridge PWM motor drivers

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity (PCS)
8N80F	AP8N80F	TO-220F	-	-	1000

ABSOLUTE MAXIMUM RATINGS ($T_a=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	800	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current ($T_c = 25^\circ\text{C}$)	I_D	8	A
Continuous Drain Current ($T_c = 100^\circ\text{C}$)	I_D	5.1	A
Pulsed Source Current ⁽¹⁾	I_{sm}	32	A
Pulsed Drain Current ⁽¹⁾	I_{DM}	32	A
Single Pulsed Avalanche Energy ⁽²⁾	E_{AS}	534	mJ
Power Dissipation	P_D	57	W
Thermal Resistance from Junction to Case	$R_{\theta JC}$	2.19	$^\circ\text{C/W}$
Thermal Resistance from Junction to Ambient	$R_{\theta JA}$	120	$^\circ\text{C/W}$
Junction Temperature	T_J	150	$^\circ\text{C}$
Storage Temperature	T_{STG}	-55~ +150	$^\circ\text{C}$

MOSFET ELECTRICAL CHARACTERISTICS(T_a=25°C unless otherwise noted)

Parameter	Symbol	Test Condition	Min	Type	Max	Unit
Static Characteristics						
Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D =250μA	800	-	-	V
Zero gate voltage drain current	I _{DSS}	V _{DS} =800V, V _{GS} = 0V, T _J =25°C	-	-	1	μA
Gate-body leakage current	I _{GSS}	V _{GS} = ±30V, V _{DS} = 0V	-	-	±100	nA
Gate threshold voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	2.0	-	4.0	V
Drain-source on-resistance ⁽³⁾	R _{DS(on)}	V _{GS} =10V, I _D =4A	-	1.42	1.55	Ω
Dynamic characteristics						
Input Capacitance	C _{iss}	V _{DS} =25V, V _{GS} =0V, f =1.0MHz	-	1083	-	pF
Output Capacitance	C _{oss}		-	103	-	
Reverse Transfer Capacitance	C _{rss}		-	5.8	-	
Switching characteristics						
Turn-on delay time	t _{d(on)}	V _{DD} =400V, I _D =8A, R _G =25Ω	-	30.33	-	ns
Turn-on rise time	t _r		-	67.0	-	
Turn-off delay time	t _{d(off)}		-	58.0	-	
Turn-off fall time	t _f		-	38.33	-	
Total Gate Charge	Q _g	V _{DS} =640V, I _D =8A, V _{GS} =10V	-	24.62	-	nC
Gate-Source Charge	Q _{gs}		-	7.26	-	
Gate-Drain Charge	Q _{gd}		-	8.97	-	
Source-Drain Diode characteristics						
Diode Forward voltage	V _{SD}	T _J =25°C, V _{GS} =0V, I _S =8A	-	-	1.4	V
Diode Forward current	I _S	T _C =25°C	-	-	8.0	A
Body Diode Reverse Recovery Time	t _{rr}	T _J =25°C, I _F =8A, di/dt=100A/us		310		ns
Body Diode Reverse Recovery Charge	Q _{rr}	T _J =25°C, I _F =8A, di/dt=100A/us		0.53		uc

Notes:

1. L=30mH, I_{AS}=5.50A, V_{DD}=135V, R_G=25Ω, starting T_J=25°C;
2. Pulse Test: Pulse width ≤300 μ s, Duty cycle ≤2%;
3. Essentially independent of operating temperature.

TYPICAL CHARACTERISTICS

Figure 1. On-Region Characteristics

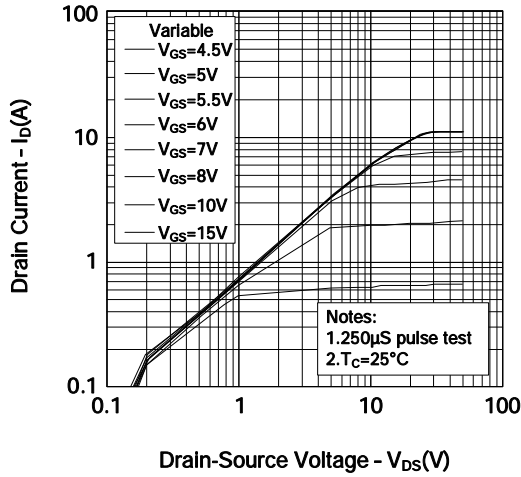


Figure 2. Transfer Characteristics

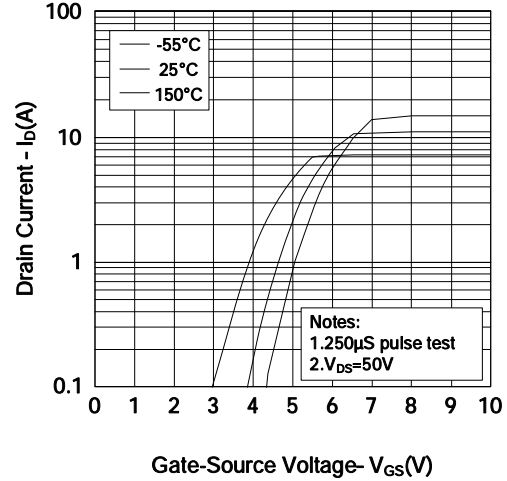


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

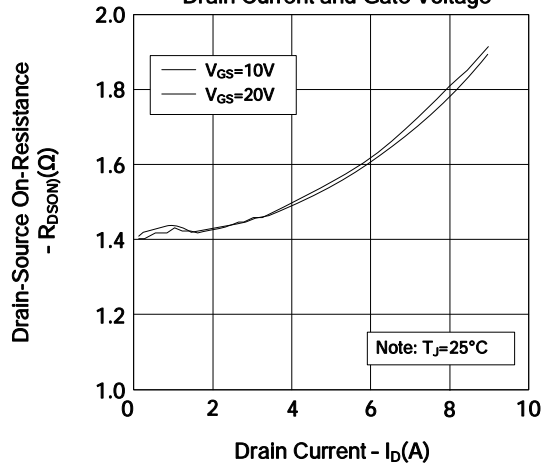


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

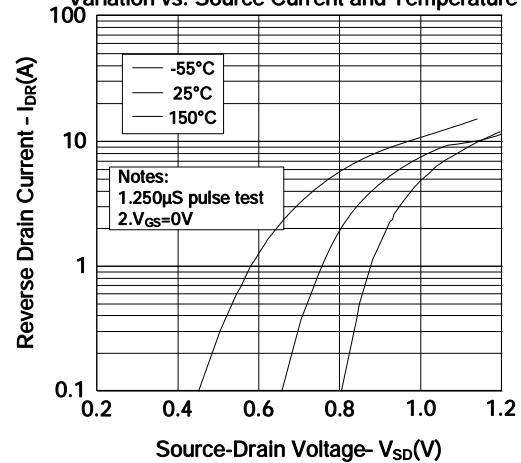


Figure 5. Capacitance Characteristics

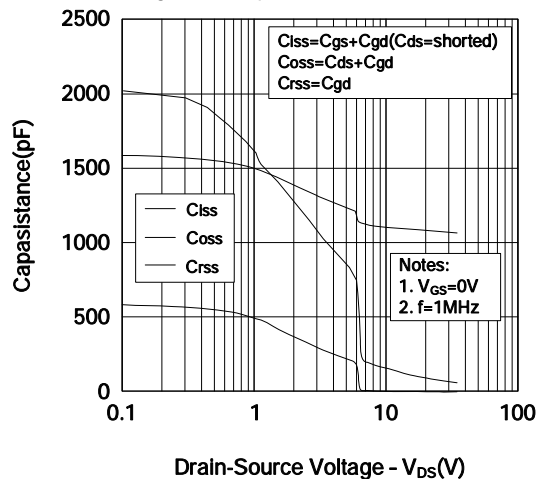
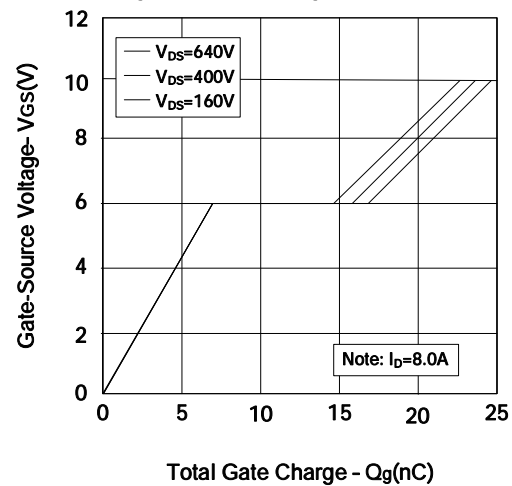


Figure 6. Gate Charge Characteristics



TYPICAL CHARACTERISTICS(continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

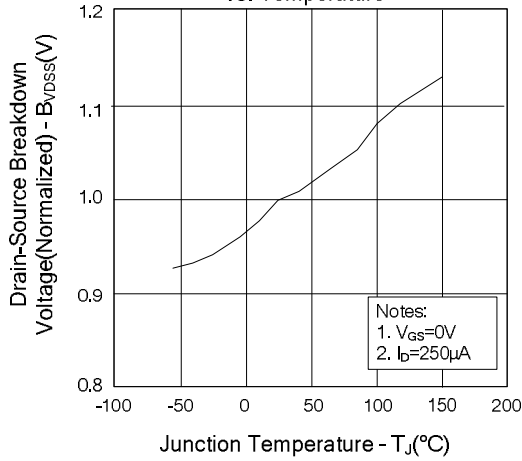


Figure 8. On-resistance Variation vs. Temperature

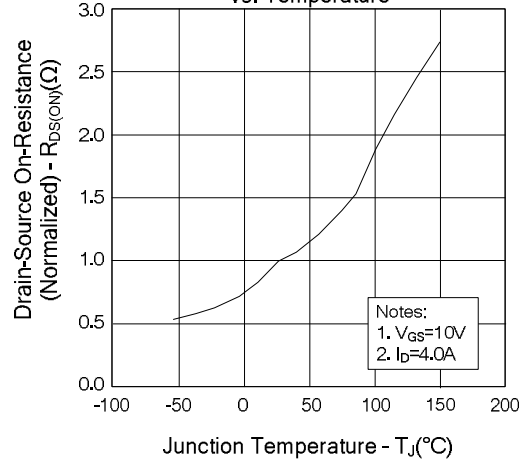


Figure 9-1. Max. Safe Operating Area (SFP8N80)

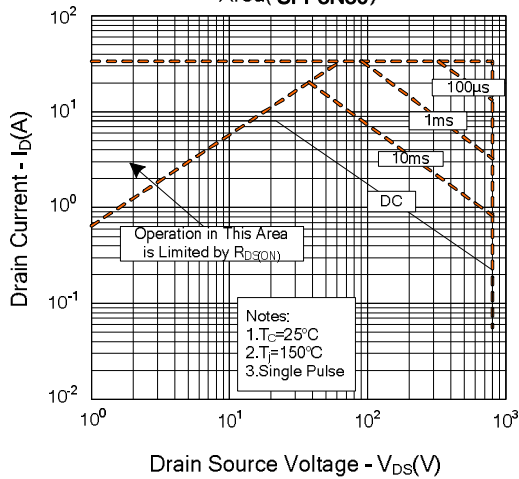


Figure 9-2. Max. Safe Operating Area (SFF8N80)

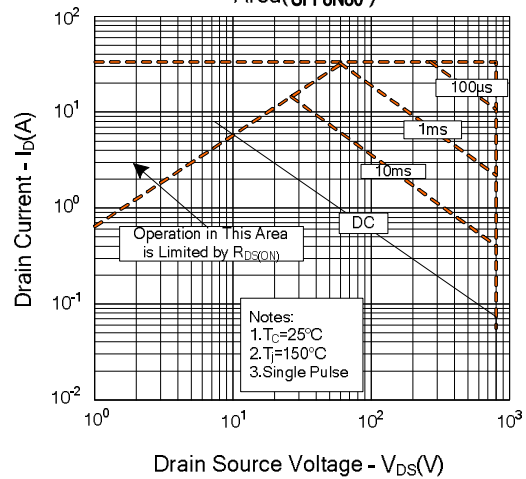
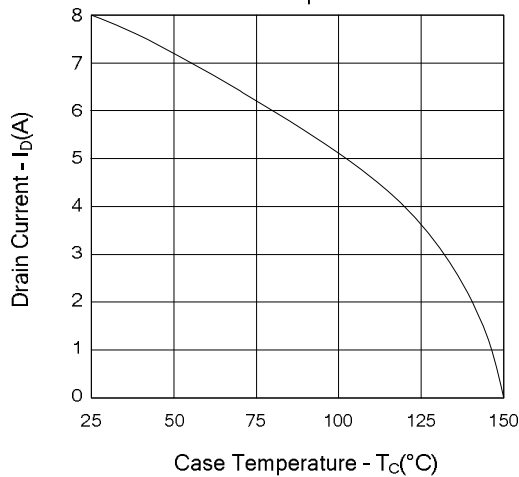
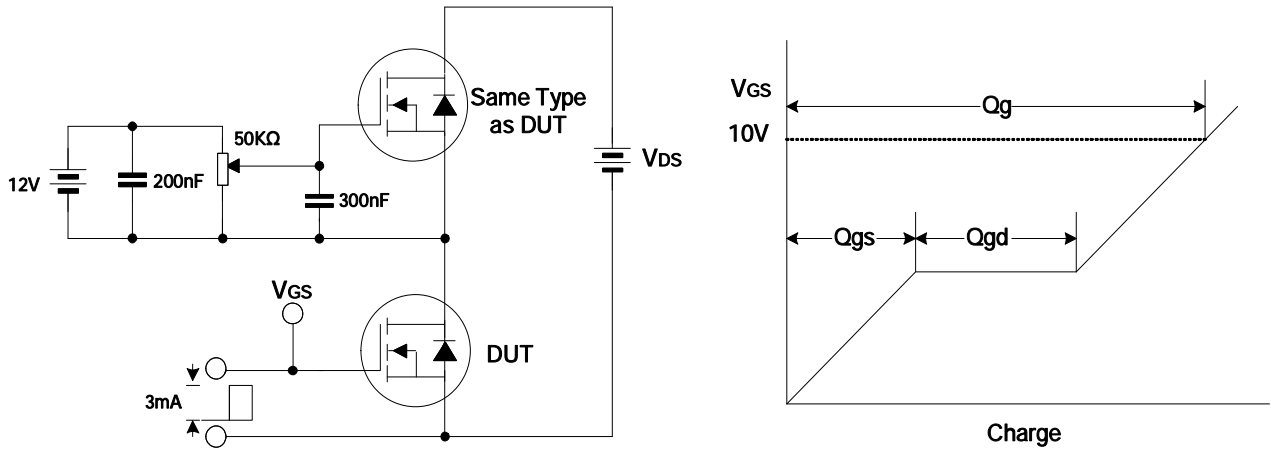


Figure 10. Maximum Drain Current vs. Case Temperature

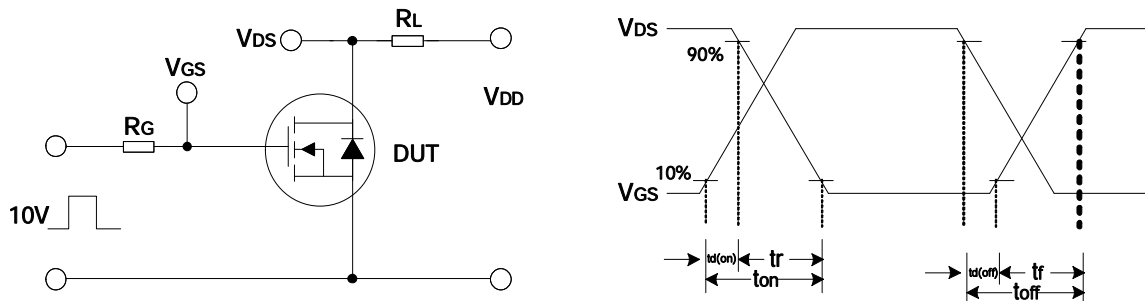


TYPICAL TEST CIRCUIT

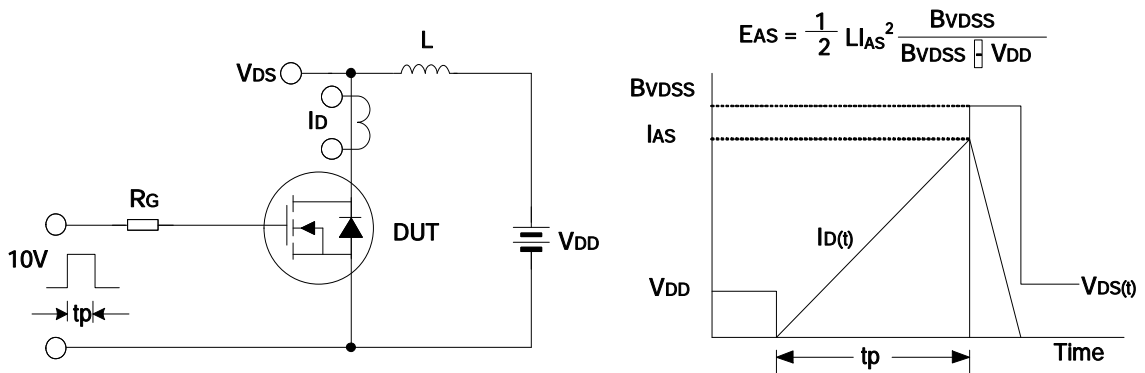
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform



Unclamped Inductive Switching Test Circuit & Waveform



AP8N80F
N-Channel Enhancement Mosfet

PACKAGE OUTLINE (continued)

